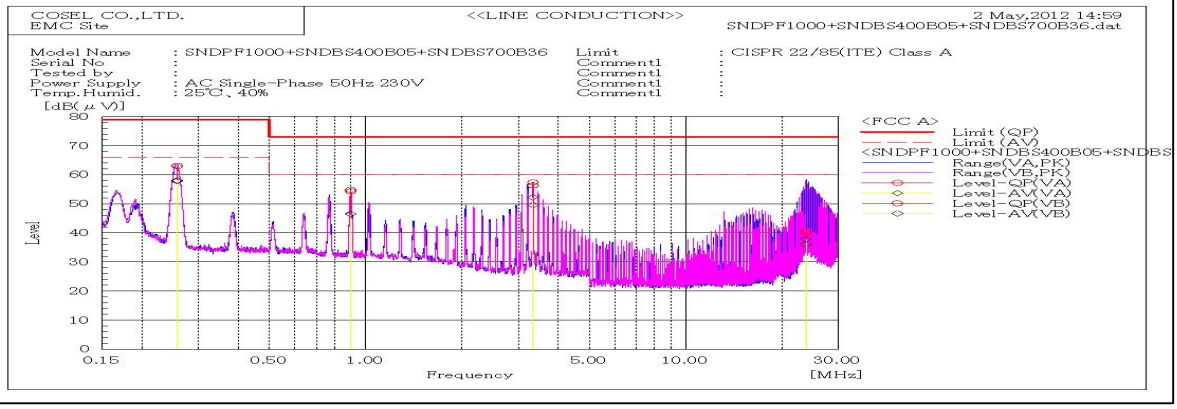
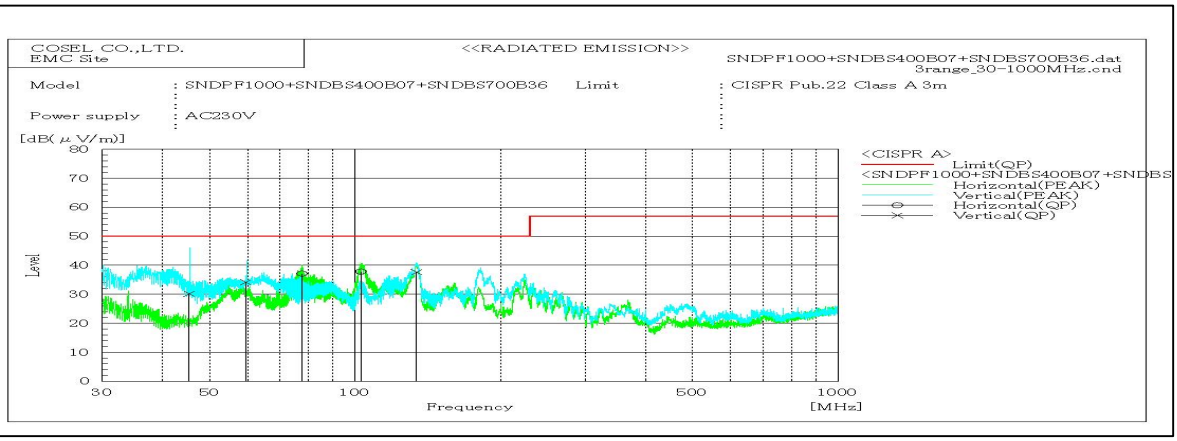
COSEL

DATA SHEET		Date	03-Aug-12
Model	SNDPF1000+SNDBS400B05+SNDBS700B36	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Satoshi.Kinoshita



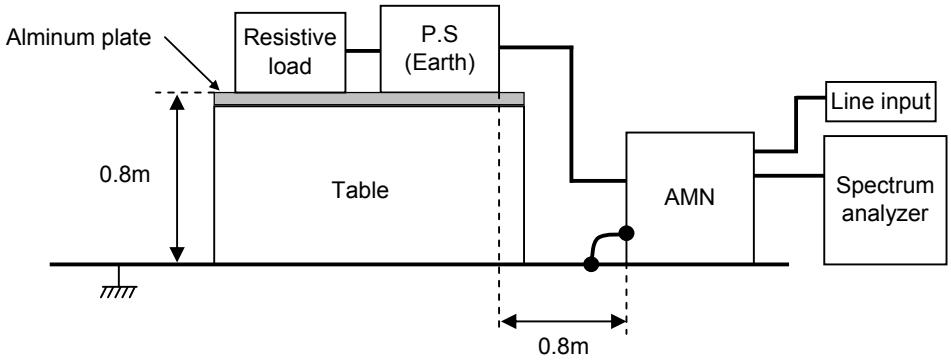
Frequency MHz	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
		QP	AV		QP	AV	QP	AV	QP	AV		
0.25727	VB	52.9	47.9	10.1	63	58	79	66	16	8	Pass	
0.25667	VA	52.9	47.7	10.1	63	57.8	79	66	16	8.2	Pass	
0.89707	VA	44.6	36.4	10.1	54.7	46.5	73	60	18.3	13.5	Pass	
0.89731	VB	44.2	36.3	10.1	54.3	46.4	73	60	18.7	13.6	Pass	
3.33069	VB	47.2	42	10.2	57.4	52.2	73	60	15.6	7.8	Pass	
3.33249	VA	46.1	39.4	10.2	56.3	49.6	73	60	16.7	10.4	Pass	
23.7944	VB	29	26.8	11	40	37.8	73	60	33	22.2	Pass	
23.8158	VA	29.6	25.1	11	40.6	36.1	73	60	32.4	23.9	Pass	



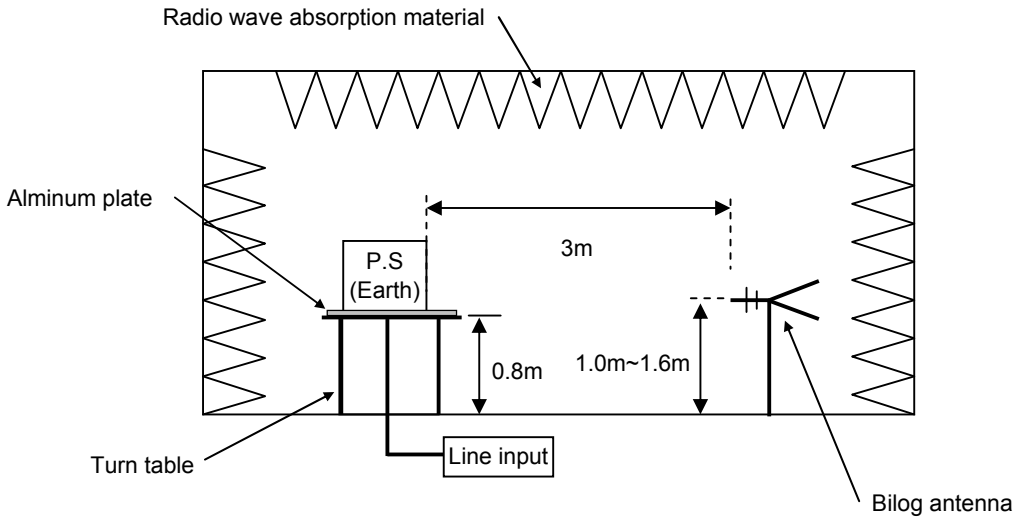
Frequency MHz	Polarization	Stability	Reading dB(uV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP		QP	QP	QP				
45.397	V	Stable	50.3	-20.2	30.1	50	19.9	Pass	104	210	
59.431	V	Stable	58.4	-24.2	34.2	50	15.8	Pass	109	336	
77.722	H	Stable	59.3	-22.1	37.2	50	12.8	Pass	151	349	
102.852	H	Stable	59.2	-21.4	37.8	50	12.2	Pass	154	3	
134.143	V	Stable	55	-17.4	37.6	50	12.4	Pass	137	139	

DATA SHEET		Date	03-Aug-12
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Satoshi.Kinoshita

1. Line conduction



2. Radiated emission



Test: EMI

Model Name:SNDPF1000+SNDBS400B05+SNDBS700B36

○ Test Circuit

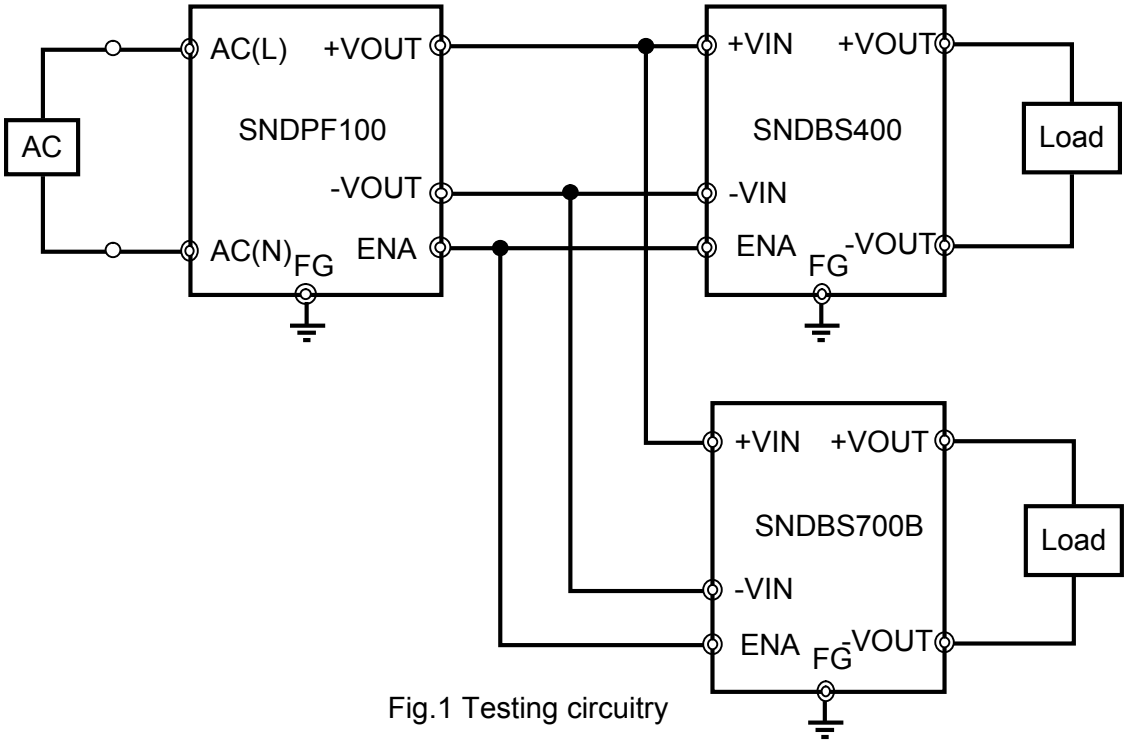
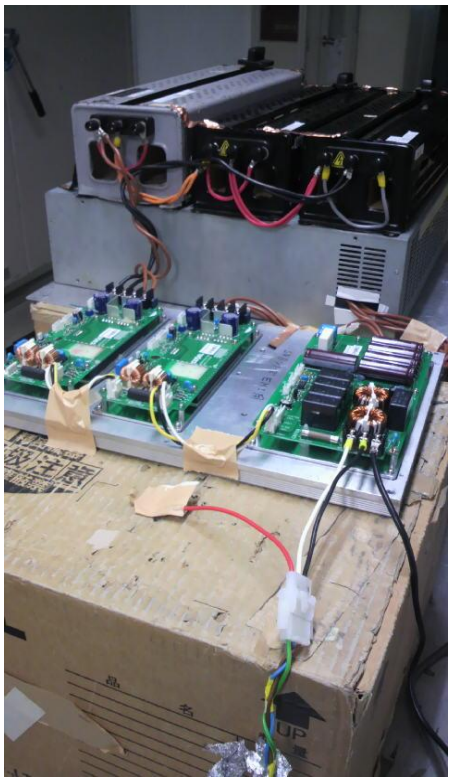


Fig.1 Testing circuitry

○ Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION